

**Search Notes**

Application/Control No.

10/564,827

Examiner

TIEN DINH

Applicant(s)/Patent under  
Reexamination

HUBER ET AL.

Art Unit

3644

**SEARCHED**

Class	Subclass	Date	Examiner
244	118.1, 118.2, 137.1		
414	532		
410	92,52		
105	375	12/2/2011	/TD/

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
244	118.1		
	118.2	12/2/2011	/TD/

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text	12/2/2011	/TD/